# PIC18F24/25/44/45K20 Device IDs Rev. 0xA Through 0x11 Silicon Errata and Data Sheet Clarification

The PIC18F24/25/44/45K20 family devices that you have received conform functionally to the current Device Data Sheet (DS41303F), except for the anomalies described in this document.

The silicon issues discussed in the following pages are for silicon revisions with the Device and Revision IDs listed in Table 1. The silicon issues are summarized in Table 2.

The errata described in this document will be addressed in future revisions of the PIC18F24/25/44/45K20 silicon.

**Note:** This document summarizes all silicon errata issues from all specified revisions of silicon.

Data Sheet clarifications and corrections start on page 8, following the discussion of silicon issues.

The silicon revision level can be identified using the current version of MPLAB<sup>®</sup> IDE and Microchip's programmers, debuggers, and emulation tools, which are available at the Microchip corporate web site (www.microchip.com).

For example, to identify the silicon revision level using MPLAB IDE in conjunction with MPLAB ICD 2 or PICkit<sup>TM</sup> 3:

- Using the appropriate interface, connect the device to the MPLAB ICD 2 programmer/ debugger or PICkit™ 3.
- From the main menu in MPLAB IDE, select <u>Configure>Select Device</u>, and then select the target part number in the dialog box.
- Select the MPLAB hardware tool (<u>Debugger>Select Tool</u>).
- Perform a "Connect" operation to the device (<u>Debugger>Connect</u>). Depending on the development tool used, the part number and Device Revision ID value appear in the **Output** window.

**Note:** If you are unable to extract the silicon revision level, please contact your local Microchip sales office for assistance.

The DEVREV values for the various PIC18F24/25/44/45K20 silicon revisions are shown in Table 1.

TABLE 1: SILICON DEVREV VALUES

Part Number	Device ID <sup>(1)</sup> (11-bit)	Revis	Revision ID for Silicon Revision <sup>(2)</sup> (5-bit)				
Part Number	Device ID. 7 (11-bit)	A4	A7	A9	AB		
PIC18F24K20	105h	0xA	0xC	0xE	0x11		
PIC18F25K20	103h	0xA	0xC	0xE	0x11		
PIC18F44K20	104h	0xA	0xC	0xE	0x11		
PIC18F45K20	102h	0xA	0xC	0xE	0x11		

- **Note 1:** The Device IDs (DEVID and DEVREV) are located at the last two implemented addresses of configuration memory space. They are shown in hexadecimal in the format "DEVID:DEVREV".
  - 2: Refer to the "PIC18F2XK20/4XK20 Flash Memory Programming Specification" (DS41297) for detailed information on Device and Revision IDs for your specific device.
  - 3: If your device contains a revision ID code that is greater than 0x11, please refer to DS80425 for silicon errata and data sheet clarifications.

TABLE 2: SILICON ISSUE SUMMARY

Module	Facture	Item	lacua Summani	Affe	cted R	evisio	ns <sup>(1)</sup>
Module	Feature	Number	Issue Summary	A4	A7	A9	AB
ECCP	CCP1CON	1.	Changing CCP1M bits may cause capture of Timer1 value.	Х	Х	Х	Х
ECCP	Full Bridge Mode	2.	Direction change issue.	Х	Х	Х	Х
MSSP SPI	SPI Clock	3.	Shortened SPI high time.	Х	Х	Х	Х
MSSP I <sup>2</sup> C™	Slew Rate	4.	Slow slew rate when SLRCON<2> is set.	Х	Х	Х	Х
ADC	Offset	5.	Time dependent on offset.	Х	Х	Х	Х
MSSP I <sup>2</sup> C	Receiving	6.	Address may be received as data.	Х	Х	Х	Х
MSSP I <sup>2</sup> C	Master Mode	7.	Master mode not functional.	Х			
MSSP SPI	SPI Master	8.	Improper sampling of last bit.	Χ	Χ	Χ	Х
MSSP SPI	SPI Master	9.	SSPBUF improperly reloads on SS pin transitions.	Х	Х	Х	Х
MSSP SPI	SPI Master	10.	Improper extra pulse on SCK pin.	Х	Х	Х	Х
EUSART	Synchronous Master Mode	11.	Duty cycle of CK output is skewed when SPBRG is odd.	Х	Х	Х	Х
EUSART	Synchronous Master Mode	12.	LS bit corruption during transmission when SPBRG = 3.	Х	Х	Х	Х
EUSART	Synchronous Master Mode	13.	Clock fails to stop at end of character transmission when SPBRG = 0.	Х	Х	Х	Х
Internal Fixed Voltage Reference (FVR)	_	14.	FVRST bit activates prematurely.	Х	Х		
High Low Voltage Detect (HLVD)	_	15.	IVRST bit activates prematurely.	Х	Х		
BOR	FVR	16.	Unexpected BOR occurrence.	Х	Х		
System Clocks	_	17.	HFINTOSC output accuracy.	Х	Х	Х	Х
POR/BOR	_	18.	Unexpected code execution at low VDD.	Х	Х	Х	Х
POR	_	19.	Premature POR release.	Х	Χ	Х	Х
POR	_	20.	POR may become stuck.	Х	Х	Χ	Х
Clocks	EC Mode	21.	48 MHz maximum frequency.	Х	Χ		
Comparators	Interrupt-on- Change	22.	Presetting interrupt-on-change issue.	Х	Х	Х	Х
Data EEPROM Memory	Endurance	23.	Endurance is limited to 10K cycles.	Х	Х	Х	Х
Program Flash Memory	Endurance	24.	Endurance is limited to 1K cycles.	Х	Х	Х	Х
Configuration Bits	CONFIG3H	25.	HFOFST bit erases to '0' instead of '1'.	Х	Х	Х	Х
EUSART	Asynchronous Receive Mode	26.	RCIDL bit may stay low improperly.	Х	Х	Х	Х
PORTB	Interrupt-on- Change	27.	False interrupt when setting interrupt enable.	Х	Х	Х	Х
ADC	ADC Conversion	28.	ADC conversion may be limited to half scale.	Х	Х	Х	Х

Note 1: Only those issues indicated in the last column apply to the current silicon revision.

#### Silicon Errata Issues

**Note:** This document summarizes all silicon errata issues from all specified revisions of silicon.

#### 1. Module: ECCP

Changing the CCP1M<3:0> bits of CCP1CON may cause the CCPR1H and CCPR1L registers to capture the value of Timer1.

#### Work around

Halt Timer1 before changing ECCP mode. Reload Timer1 with desired value after ECCP is setup and before Timer1 is restarted.

#### **Affected Silicon Revisions**

A4	Α7	<b>A9</b>	AB		
Χ	Χ	Х	Χ		

#### 2. Module: ECCP

Changing direction in Full-Bridge mode does not insert dead time between changing the active drivers in common legs of the bridge.

#### Work around

None.

#### **Affected Silicon Revisions**

<b>A4</b>	A7	Α9	AB		
Χ	Х	Х	Х		

#### 3. Module: MSSP SPI

When the SPI clock is configured for Timer2/2 (SSPCON1<3:0> = 0011), the first SPI high time may be short.

#### Work around

Option 1: Ensure TMR2 value rolls over to zero immediately before writing to SSPBUF.

Option 2: Turn Timer2 off and clear TMR2 before writing SSPBUF. Enable TMR2 after SSPBUF is written.

#### **Affected Silicon Revisions**

A4	Α7	A9	AB		
Χ	Χ	Χ	Χ		

#### 4. Module: MSSP I<sup>2</sup>C™

Slew rate is slower than I<sup>2</sup>C specifications when the SLRCON<2> bit is set.

#### Work around

Clear SLRCON<2> bit when using the I<sup>2</sup>C peripheral.

#### **Affected Silicon Revisions**

<b>A4</b>	A7	A9	AB		
Χ	Χ	Χ	Х		

#### 5. Module: ADC

Offset error is 3 LSb typical, 7 LSb maximum, including an acquisition time dependent component (~2 LSb).

#### Work around

The time dependent error is insignificant when the time between conversions is less than 100 ms. When the time since the previous conversion is greater than 100 ms then take two ADC conversions and discard the first.

#### **Affected Silicon Revisions**

A4	A7	<b>A9</b>	AB		
Χ	Χ	Χ	Χ		

### 6. Module: MSSP I<sup>2</sup>C

If a new address byte is received while the BF flag is set, the SSPOV bit is properly set and an ACK is properly not generated. If only the SSPOV bit is set (BF flag was cleared) and a matching address is clocked in, that received byte will be improperly loaded into the SSPBUF register and an ACK will be improperly generated.

#### Work around

None.

#### **Affected Silicon Revisions**

A4	Α7	A9	AB		
Χ	Χ	Χ	Χ		

### 7. Module: MSSP I<sup>2</sup>C

I<sup>2</sup>C Master mode is not functional (Rev. A4 only).

#### Work around

Use software to emulate Master mode.

A4	A7	A9	AB		
Χ					

#### 8. Module: MSSP SPI

In SPI Master mode, when the CKE bit is cleared and the SMP bit is set, the last bit of the incoming data stream (bit 0) at the SDI pin will not be sampled properly.

#### Work around

None.

#### **Affected Silicon Revisions**

A4	A7	А9	AB		
Х	Х	Х	Х		

#### 9. Module: MSSP SPI

In SPI Master mode, when CKE bit is set, the SSPBUF will reload the SSPSR output shift register on every high-to-low transition of the  $\overline{SS}$  pin.

#### **Work around**

Avoid using the  $\overline{SS}$  pin when the CKE bit is set and the MSSP is configured for SPI Master mode.

#### **Affected Silicon Revisions**

<b>A4</b>	A7	Α9	AB		
Χ	Х	Χ	Х		

#### 10. Module: MSSP SPI

When SPI is enabled in Master mode with CKE = 1 and CKP = 0, a 1/Fosc wide pulse will occur on the SCK pin.

#### Work around

Configure SCK pin as an input until after the MSSP is setup.

#### **Affected Silicon Revisions**

A4	Α7	A9	AB		
Χ	Χ	Χ	Χ		

#### 11. Module: EUSART

In Synchronous Master mode, when the SPBRG is set to an odd number, the duty cycle of the CK output will be skewed by one baud clock count.

#### Work around

High values of SPBRG will minimize the effect of this anomaly.

#### **Affected Silicon Revisions**

A4	A7	<b>A9</b>	AB		
Χ	Х	Χ	Х		

#### 12. Module: EUSART

In Synchronous Master mode, when the SPBRG is set to 3 and the TXREG is written while the previous character is still in the TX shift register, the LS bit of the TXREG character may be corrupted during transmission.

#### Work around

When SPBRG is set to 3, wait until the TRMT bit of the TXSTA register is set before loading TXREG with the next character to be transmitted.

#### Affected Silicon Revisions

A4	Α7	A9	AB		
Χ	Χ	Χ	Χ		

#### 13. Module: EUSART

In Synchronous Master mode, if the SPBRG register is equal to 0 when the TXEN bit is set, then writing to TXREG will properly start transmission. However, the clock will be improperly out of phase with the data bits and the clock will not stop at the end of the character transmission.

#### Work around

Set SPBRG register to non-zero value before setting the TXEN bit.

#### **Affected Silicon Revisions**

A4	Α7	A9	AB		
Χ	Х	Х	Х		

## 14. Module: Internal Fixed Voltage Reference (FVR)

The FVRST bit of the CVRCON2 register activates prematurely (Rev. A4 and A7 only).

#### Work around

Wait an additional 20  $\mu s$  after FVRST is sensed high before using the fixed voltage reference. Enable the FVR by setting the FVREN bit of the CVRCON2 register before activating any peripheral that automatically enables the FVR. Peripherals that automatically enable the FVR include the Brown-out Reset, the High/Low Voltage Detect, and the HFINTOSC.

A4	A7	A9	AB		
Χ	Χ				

#### 15. Module: High Low Voltage Detect (HLVD)

The IVRST bit of the HLVDCON register activates prematurely (Rev. A4 and A7 only).

#### Work around

Wait an additional 20  $\mu s$  after IVRST is sensed high before using the fixed voltage reference. Enable the FVR by setting the FVREN bit of the CVRCON2 register before activating any peripheral that automatically enables the FVR. Peripherals that automatically enable the FVR include the Brown-out Reset, the High/Low Voltage Detect, and the HFINTOSC.

#### **Affected Silicon Revisions**

	A4	Α7	A9	AB		
ľ	Χ	Χ				

#### 16. Module: BOR

An unexpected Brown-out Reset may occur when the fixed voltage reference is inactive and BOR is activated, thereby activating the fixed voltage reference simultaneously. This error is caused by a premature FVRST stable flag (Rev. A4 and A7 only).

#### Work around

Enable the FVR by setting the FVREN bit of the CVRCON2 register and then wait an additional 20 µs after FVRST is sensed high before enabling BOR. Brown-out disable in Sleep mode with automatic enable on wake-up cannot be used.

#### **Affected Silicon Revisions**

A4	Α7	A9	AB		
Χ	Χ				

#### 17. Module: System Clocks

HFINTOSC output frequency is 16 MHz  $\pm$  3% 25°C to 85°C.

#### Work around

None.

#### **Affected Silicon Revisions**

A4	Α7	A9	AB		
Χ	Χ	Χ	Χ		

#### 18. Module: POR/BOR

The POR rearm voltage may be below the low end of the BOR range causing unexpected code execution below the BOR range.

#### Work around

Use external power monitor to hold device in Reset below 1.1 Volts.

#### **Affected Silicon Revisions**

<b>A4</b>	Α7	A9	AB		
Χ	Χ	Χ	Χ		

#### 19. Module: POR

The POR may release around 0.8 volts (below the POR rearm voltage of 1.2V nominal) when VDD rises from below either 0.60V (when BOR is not enabled) or 0.33V (when BOR is enabled).

#### Work around

Use Power-up Timer when operating with the EC, EXTRC or HFINTOSC oscillator modes. Ensure that VDD rise time is less than the Power-up Timer time.

#### **Affected Silicon Revisions**

<b>A4</b>	A7	Α9	AB		
Χ	Х	Х	Х		

#### 20. Module: POR

The part may hang in the Reset state when VDD rises to the operating range at a rate faster than 7500 volts per second. Recovery from the hung state is possible only by first lowering VDD to below 0.3V followed by raising VDD to the operating range.

#### Work around

Slow VDD rise time by adding series resistance between the voltage supply and the VDD pin and increasing the VDD bypass capacitance. VDD bypassing should remain on the pin side of the series resistor.

A4	A7	A9	AB		
Χ	Х	Х	Х		

#### 21. Module: Clocks

EC Mode operation is limited to a maximum of 48 MHz (Rev. A4 and A7 only).

#### Work around

Divide external clock by 4 and use HS-PLL Clock mode for external clocking above 48 MHz.

#### **Affected Silicon Revisions**

<b>A4</b>	A7	A9	AB		
Χ	Х				

#### 22. Module: Comparators

When the CxON bit is clear, the output from the comparator will be properly forced to zero, but the CxPOL bit will improperly have no effect on the CxOUT bit. This prevents presetting the comparator change-on-interrupt mismatch latches as described in the data sheet.

#### Work around

Configure one of the unused comparator input channels as a digital output. Use that digital output to manipulate the comparator output to the desired CxOUT non-interrupt level. When the comparator is then set to the desired inputs, the mismatch latches will be preset to the non-interrupt level and the CxIF flag can then be cleared.

#### **Affected Silicon Revisions**

<b>A4</b>	Α7	A9	AB		
Χ	Χ	Χ	Χ		

#### 23. Module: Data EEPROM Memory

The write/erase endurance of Data EE Memory is limited to 10K cycles.

#### Work around

Use error correction method that stores data in multiple locations.

#### **Affected Silicon Revisions**

A4	A7	A9	AB		
Χ	Χ	Χ	Х		

#### 24. Module: Program Flash Memory

The write/erase endurance of the PFM is limited to 1K cycles when VDD is above 3V. Endurance degrades when VDD is below 3V.

#### Work around

For data tables in program Flash memory use error correction method that stores data in multiple locations.

#### **Affected Silicon Revisions**

A4	A7	Α9	AB		
Χ	Х	Х	Х		

#### 25. Module: Configuration Bits

Bit 3 of CONFIG3H defaults to '0' after a Bulk Erase instead of '1' as specified in the data sheet.

#### Work around

Program the HFOFST bit to the desired state after a Bulk Erase. All MPLAB® IDE programming tools currently perform this way.

#### **Affected Silicon Revisions**

<b>A4</b>	A7	<b>A9</b>	AB		
Χ	Χ	Χ	Χ		

#### 26. Module: EUSART

In Asynchronous Receive mode, the RCIDL bit of the BAUDCON register will properly go low when an invalid Start bit less than 1/8th of a bit time is received. The RCIDL bit will then stay low improperly until a valid Start bit is received.

#### Work around

When monitoring the RCIDL bit, measure the length of time between the RCIDL going low and the RCIF flag going high. If this time is greater than one character time, then restore the RCIDL bit by resetting the EUSART module. The EUSART module is reset when the SPEN bit of the RCSTA register is cleared.

A4	A7	A9	AB		
Х	Х	Х	Х		

#### 27. Module: PORTB

Setting a PORTB Interrupt-on-change enable bit of the IOCB register while the corresponding PORTB input is high will cause an RBIF interrupt.

#### Work around

Set the IOCB bits to the desired configuration then read PORTB to clear the mismatch latches. Finally, clear the RBIF bit before setting the RBIE bit.

#### **Affected Silicon Revisions**

A4	A7	<b>A9</b>	AB		
Х	Х	Х	Х		

#### 28. Module: ADC

After extended stress the Most Significant bit (MSb) of the ADC conversion result can become stuck at '0'. Conversions resulting in code 511 or less are still accurate, but conversions that should result in codes greater than 511 are instead pinned at 511.

The potential for failures is a function of several factors:

- The potential for failures increases over the life of the part. No failures have ever been seen for accelerated stress estimated to be equivalent to 34 years at room temperature. The failure rate after accelerated stress estimated to be equivalent to 146 years at room temperature can be as high as 10% for VDD = 1.8V. The time to failure will decrease as the operating temperature increases.
- The potential for failures is highest at low VDD and decreases as VDD increases.
- The potential for failures depends on the settings of the ADCW<2:0> and ACQT<2:0> bits in ADCON2:

ADCS<2:0>	ACQT<2:0> = 000	<b>ACQT&lt;2:0&gt;</b> ≠ 000
011 or 111	No Failures	Low Probability
000	Very Low Probability	Low Probability
001, 010, 100, 101, <b>or</b> 110	Moderate Probability	Moderate Probability

#### Work around

- Restrict the input voltage to less than 1/2 of the ADC voltage reference so that the expected result is always a code less than or equal to 511.
- 2. Use manual acquisition time (ACQT<2:0> = 000) and use the ADC's dedicated internal oscillator as the conversion clock source (ADCS<2:0>) = 011 or 111).
- 3. Use manual acquisition time (ACQT<2:0> = 000) and put the part to Sleep after each conversion.

A4	A7	<b>A9</b>	AB		
Χ	Χ	Χ	Χ		

#### **Data Sheet Clarifications**

The following typographic corrections and clarifications are to be noted for the latest version of the device data sheet (DS41303 $\mathbf{F}$ ):

**Note:** Corrections are shown in **bold**. Where possible, the original bold text formatting has been removed for clarity.

None.

# APPENDIX A: DOCUMENT REVISION HISTORY

#### Rev A Document (02/2008)

First revision of this document.

#### Rev B Document (05/12/08)

Added Module 20: POR, updating subsequent numbering. Updated Module 5: ADC, Work around description. Added Module 8 MSSP I<sup>2</sup>C, updating subsequent numbering. Revised Module 22: Clocks, added silicon revs.

#### Rev C Document (08/2008)

Revised Module 22; Added Modules 27 and 28.

#### Rev D Document (01/2009)

Revised Module 21; Added Module 29.

#### Rev E Document (05/2009)

Updated Errata to new format; Deleted Module 8: MSSP I<sup>2</sup>C and Module 23: Comparators; Renumbered Modules; Added Module 28: ADC; minor edits.

Clarifications/Corrections to the Data Sheet: Added Module 1: MSSP; Module 2: Electrical Specifications; Module 3: Electrical Specifications.

#### Rev F Document (06/2009)

Clarifications/Corrections to the Data Sheet:

Deleted Module 1: MSSP: Figure 17-17 Baud Rate Generator Block Diagram, updating subsequent numbering. Added Module 3 MSSP: Register 17-3 SSPADD; Added Module 4 MSSP: Section 17.4.2 Operation; Added Module 5 MSSP: Figure 17-16 MSSP Block Diagram; Added Module 6 MSSP: Sections 17.4.7.1, 17.4.8, 17.4.9, 17.4.17.1, 17.4.17.2, 17.4.17.3: SSPADD, changing <6:0> to <7:0>.

#### Rev G Document (10/2009)

Updated the title of the errata.

Data Sheet Clarifications: Updated the errata deleting Modules 1, 2, 3, 4, 5, 6.

NOTES:

#### Note the following details of the code protection feature on Microchip devices:

- · Microchip products meet the specification contained in their particular Microchip Data Sheet.
- Microchip believes that its family of products is one of the most secure families of its kind on the market today, when used in the intended manner and under normal conditions.
- There are dishonest and possibly illegal methods used to breach the code protection feature. All of these methods, to our
  knowledge, require using the Microchip products in a manner outside the operating specifications contained in Microchip's Data
  Sheets. Most likely, the person doing so is engaged in theft of intellectual property.
- Microchip is willing to work with the customer who is concerned about the integrity of their code.
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